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... Chune-Sin Yeh, and **Zhihong Liu** BTA Technology ... circuit characterization and simulation system for **hot carrier** effects (GLACIER ... O-7695-0525-2/00 \$10.00 0 2000 IEEE ...

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Ratio based hot-carrier degradation modeling for aged timing simulation of millions of transistors ...

H Yonezawa, J Fang, Y Kawakami, N Iwanishi, L Wu, ... - Electron Devices Meeting, 1998. IEDM'98 Technical Digest., ..., 1998 - ieeexplore.ieee.org

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Build-in Reliability Analysis for Circuit Design in the Nanometer Technology Era

Z Liu, W Zhang, F Mu, N Modeling - ieeexplore.ieee.org

... 0-7803-8528-4/04/\$20.00 ©2004 IEEE 205 ... Design in the Nanometer Technology Era **Zhihong**

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Gate-Level Aged Timing Simulation Methodology for Hot-Carrier Reliability Assurance

Y Kawakami, J Fang, H Yonezawa, N Iwanishi, L Wu, ... - portal.acm.org

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0-7803-5974-7 ... according to the result of the hot-carrier reliability simulation ...

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Novel self-convergent programming method using source-induced band-to-band hot electron injection

L Pan, J Zhu, Z Liu, Y Zeng, J Liu - IEEE Electron Device Letters, 2002 - ieeexplore.ieee.org

... 11, NOVEMBER 2002 ... Liyang Pan, Jun Zhu, **Zhihong Liu**, Ying Zeng, and Jianzhao Liu ... these methods, the self-converging drain avalanche **hot carrier** (DAHE) injection ...

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JD Lee, JH Choi, D Park, K Kim - IEEE ELECTRON DEVICE LETTERS, 2003 - [ieeexplore.ieee.org](http://ieeexplore.ieee.org)  
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P Machanick - springerlink.com

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integrated circuit μPD4482162, 4482182, 4482322, 4482362, December 2002. ...

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A Diwan, H Lee, D Grunwald, K Farkas - cs.colorado.edu

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### GOALSERVER: A Multiobjective Design Optimization Tool for IC Fabrication Process

L Wu, Z Yang, Z Yu, Z Li - DAC, 1991 - ieeexplore.ieee.org

... IC Fabrication Process **Lifeng Wu**, Zhilian Yang, Zhiping Yu, and Zhijian Li The

Institute of Microelectronics Tsinghua University Beijing 100084, China ...

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### Fast Decap Allocation Algorithm For Robust On-Chip Power Delivery

Z Qi, H Li, XDT Sheldon, L Wu, Y Cai, X Hong - Proceedings of the Sixth International Symposium on Quality ..., 2005 - doi.ieeecomputersociety.org

Adding on-chip decoupling capacitors (decaps) is an effective way to reduce voltage noise in power/ground networks and ensure robust power delivery. ...

Web Search - ee.ucr.edu - portal.acm.org

### Full-chip reliability simulation for VDSM integrated circuits

L Wu, Z Liu - Microelectronics and Reliability, 2001 - ingentaconnect.com

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### Partitioning-Based Approach to Fast On-Chip Decap Budgeting and Minimization

H Li, Z Qi, XDT Sheldon, L Wu, Y Cai, X Hong - Proceedings of the 42nd annual conference on Design ..., 2005 - portal.acm.org

ABSTRACT This paper proposes a fast decoupling capacitance (decap) allocation and budgeting algorithm for both early stage decap estimation and later ...

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### Gate-Level Aged Timing Simulation Methodology for Hot-Carrier Reliability Assurance

Y Kawakami, J Fang, H Yonezawa, N Iwanishi, L Wu, ... - portal.acm.org

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### Dependence of Order-Disorder Transition on the Number of Blocks for Multiblock Copolymers

L Wu, EW Cochran, TP Lodge, FS Bates - American Physical Society, Annual APS March Meeting 2003, ..., 2003 - adsabs.harvard.edu

Title: Dependence of Order-Disorder Transition on the Number of Blocks for Multiblock Copolymers Authors: Wu, Lifeng; Cochran, Eric W.; Lodge, Timothy P.; Bates ...

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### Architecture Effect on Shear Alignment of Block Copolymers

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Title: Architecture Effect on Shear Alignment of Block Copolymers Authors: Wu, Lifeng; Lodge, Timothy P.; Bates, Frank S. Affiliation: Department of Chemical ...

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### SINTERING OF Ti<sub>3</sub>SiC<sub>2</sub> WITH B<sub>2</sub>O<sub>3</sub> ADDITIONS

K Tang, C Wang, L Wu, X Guo, X Xu, Y Huang - Ceramics International, 2002 - ingentaconnect.com

Titanium silicon carbide (Ti<sub>3</sub>SiC<sub>2</sub>) is a remarkable material for it combines the best properties of metals and ceramics. When Ti<sub>3</sub>SiC<sub>2</sub> is synthesized ...

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International Symposium on Quality Electronic Design, ISQED 2003. Due to the overwhelming success of the first 3 conferences, despite the slump in the ...

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